# **ON Semiconductor**

# Is Now



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# N-Channel Power MOSFET 620 V, 2.0 $\Omega$

#### **Features**

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	620		V
Continuous Drain Current R <sub>θJC</sub>	I <sub>D</sub>	4.4 4.1 (Note 2)		Α
Continuous Drain Current $R_{\theta JC}$ , $T_A = 100^{\circ}C$	I <sub>D</sub>	2.8 2.6 (Note 2)		Α
Pulsed Drain Current, V <sub>GS</sub> @ 10V	I <sub>DM</sub>	18 (Note 2)	16	Α
Power Dissipation $R_{\theta JC}$ (Note 1)	$P_{D}$	28	83	W
Gate-to-Source Voltage	V <sub>GS</sub>	±30		V
Single Pulse Avalanche Energy, I <sub>D</sub> = 4.0 A	E <sub>AS</sub>	120		mJ
ESD (HBM) (JESD22-A114)	V <sub>esd</sub>	3000		V
RMS Isolation Voltage (t = 0.3 sec., R.H. ≤ 30%, T <sub>A</sub> = 25°C) (Figure 14)	V <sub>ISO</sub>	4500 –		V
Peak Diode Recovery	dv/dt	4.5 (No	te 3)	V/ns
Continuous Source Current (Body Diode)	I <sub>S</sub>	4.0		Α
Maximum Temperature for Soldering Leads, 0.063" (1.6 mm) from Case for 10 s Package Body for 10 s	T <sub>L</sub> T <sub>PKG</sub>	300 260		°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150		°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces).
- 2. Limited by maximum junction temperature
- 3.  $I_{SD} = 4.0 \text{ A}$ , di/dt  $\leq 100 \text{ A}/\mu \text{s}$ ,  $V_{DD} \leq BV_{DSS}$ ,  $T_J = +150 ^{\circ} \text{C}$

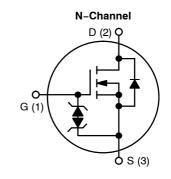
This document contains information on some products that are still under development. ON Semiconductor reserves the right to change or discontinue these products without notice.

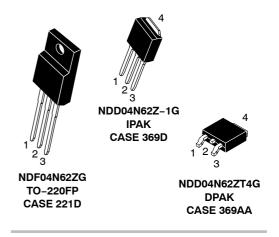


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V <sub>DSS</sub>	R <sub>DS(ON)</sub> (MAX) @ 2 A
620 V	2.0 Ω





#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

## THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF04N62Z NDD04N62Z	$R_{ heta JC}$	4.4 1.5	°C/W
Junction-to-Ambient Steady State	(Note 4) NDF04N62Z (Note 1) NDD04N62Z (Note 4) NDD04N62Z-1	$R_{ hetaJA}$	50 38 80	

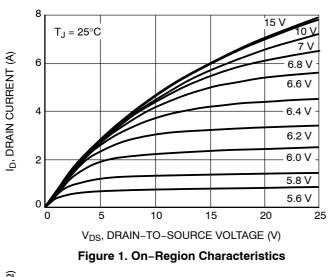
## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA		BV <sub>DSS</sub>	620			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> = 1 mA		$\Delta BV_{DSS}/ \ \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V 000 V V 0 V	25°C	I <sub>DSS</sub>			1	μΑ
	$V_{DS} = 620 \text{ V}, V_{GS} = 0 \text{ V}$	125°C				50	
Gate-to-Source Forward Leakage	V <sub>GS</sub> = ±20 V		I <sub>GSS</sub>			±10	μΑ
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2.0 \text{ A}$	Ą	R <sub>DS(on)</sub>		1.8	2.0	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 50 \mu A$	Ą	V <sub>GS(th)</sub>	3.0		4.5	V
Forward Transconductance	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2.0 A		9 <sub>FS</sub>		3.3		S
DYNAMIC CHARACTERISTICS							
Input Capacitance			C <sub>iss</sub>		535		pF
Output Capacitance	$V_{DS} = 25 \text{ V, } V_{GS} = 0 \text{ V,}$ $f = 1.0 \text{ MHz}$		C <sub>oss</sub>		62		
Reverse Transfer Capacitance			C <sub>rss</sub>		14		
Total Gate Charge	V <sub>DD</sub> = 310 V, I <sub>D</sub> = 4.0 A, V <sub>GS</sub> = 10 V		$Q_g$		19		nC
Gate-to-Source Charge			Q <sub>gs</sub>		3.9		
Gate-to-Drain ("Miller") Charge			Q <sub>gd</sub>		10		
Plateau Voltage			$V_{GP}$		6.4		V
Gate Resistance			$R_{g}$		4.7		Ω
RESISTIVE SWITCHING CHARACTERI	STICS				_	_	_
Turn-On Delay Time			t <sub>d(on)</sub>		12		ns
Rise Time	$V_{DD} = 310 \text{ V}, I_D = 4.0 \text{ A}$	۸,	t <sub>r</sub>		13		1
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 5 \Omega$		t <sub>d(off)</sub>		25		1
Fall Time			t <sub>f</sub>		14		
SOURCE-DRAIN DIODE CHARACTER	ISTICS (T <sub>C</sub> = 25°C unless other	erwise not	ed)				
Diode Forward Voltage	I <sub>S</sub> = 4.0 A, V <sub>GS</sub> = 0 V		$V_{SD}$			1.6	V
Reverse Recovery Time	V <sub>GS</sub> = 0 V, V <sub>DD</sub> = 30 V	/	t <sub>rr</sub>		285		ns
Reverse Recovery Charge	$I_S = 4.0 \text{ A}, \text{ di/dt} = 100 \text{ A}$		Q <sub>rr</sub>		1.3		μС

<sup>4.</sup> Insertion mounted

<sup>5.</sup> Pulse Width  $\leq 380~\mu\text{s},$  Duty Cycle  $\leq 2\%.$ 

#### **TYPICAL CHARACTERISTICS**



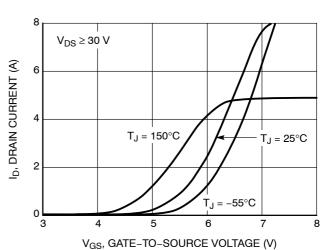


Figure 2. Transfer Characteristics

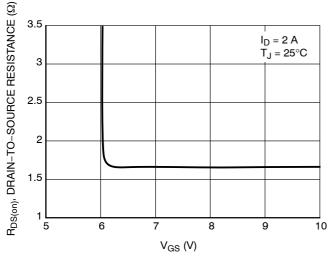


Figure 3. On-Resistance vs. Gate Voltage

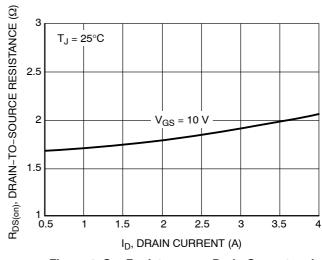


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

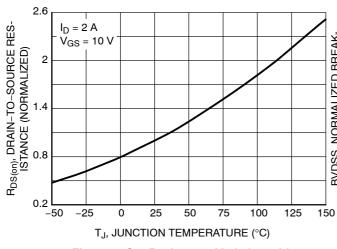


Figure 5. On–Resistance Variation with Temperature

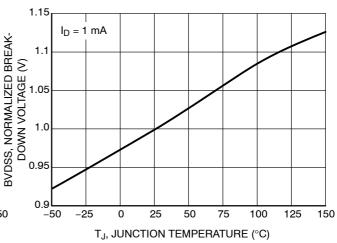


Figure 6. BVDSS Variation with Temperature

#### **TYPICAL CHARACTERISTICS**

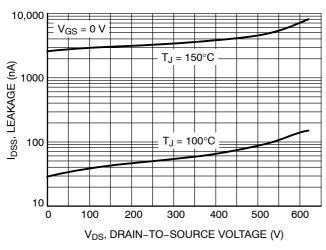


Figure 7. Drain-to-Source Leakage Current vs. Voltage

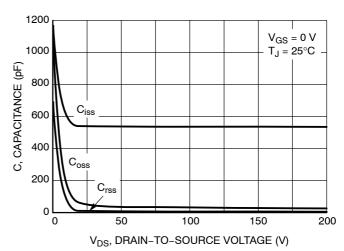


Figure 8. Capacitance Variation

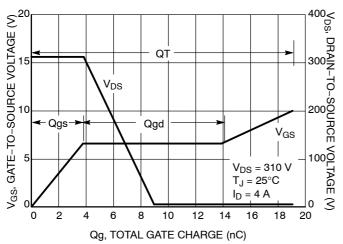


Figure 9. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

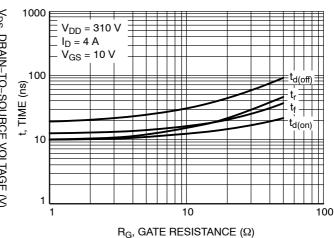


Figure 10. Resistive Switching Time Variation vs. Gate Resistance

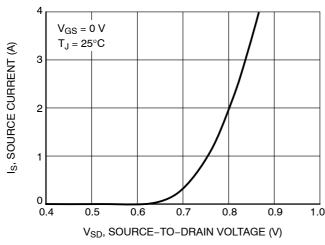


Figure 11. Diode Forward Voltage vs. Current

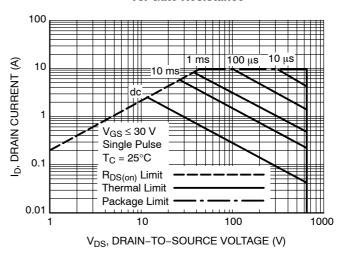


Figure 12. Maximum Rated Forward Biased Safe Operating Area for NDF04N62Z

#### **TYPICAL CHARACTERISTICS**

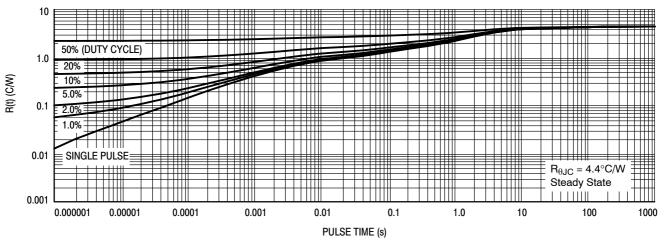


Figure 13. Thermal Impedance for NDF04N62Z

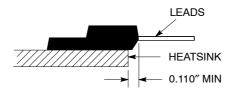


Figure 14. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

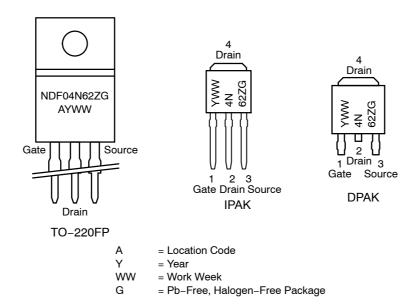
\*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NDF04N62ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD04N62Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail (In Development)
NDD04N62ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape & Reel (In Development)

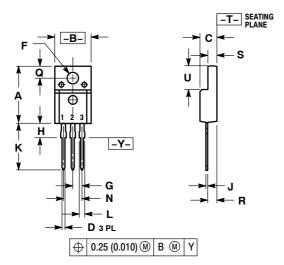
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **MARKING DIAGRAMS**



#### **PACKAGE DIMENSIONS**

#### TO-220FP CASE 221D-03 ISSUE K



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH
  3. 221D-01 THRU 221D-02 OBSOLETE, NEW STANDARD 221D-03.

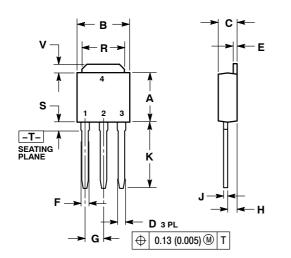
	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.617	0.635	15.67	16.12	
В	0.392	0.419	9.96	10.63	
c	0.177	0.193	4.50	4.90	
D	0.024	0.039	0.60	1.00	
F	0.116	0.129	2.95	3.28	
G	0.100 BSC		2.54	BSC	
Н	0.118	0.135	3.00	3.43	
J	0.018	0.025	0.45	0.63	
K	0.503	0.541	12.78	13.73	
L	0.048	0.058	1.23	1.47	
N	0.200	BSC	5.08 BSC		
Q	0.122	0.138	3.10	3.50	
R	0.099	0.117	2.51	2.96	
S	0.092	0.113	2.34	2.87	
U	0.239	0.271	6.06	6.88	

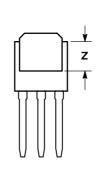
STYLE 1:

PIN 1. GATE 2. DRAIN

3. SOURCE

#### **IPAK** CASE 369D-01 ISSUE C





- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
  1. DIMENSIONING AND TOLERANCING PER
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

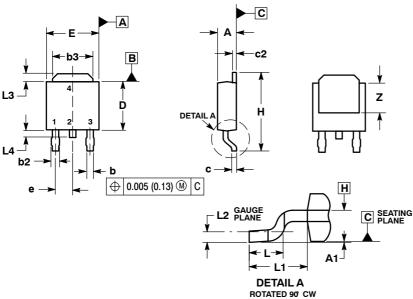
	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090 BSC		2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

- STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE
  - 4. DRAIN

#### PACKAGE DIMENSIONS

## **DPAK (SINGLE GUAGE)**

CASE 369AA-01 **ISSUE B** 



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
  3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- MENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE.

  5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

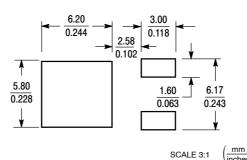
  6. DATUMS A AND B ARE DETERMINED AT DATUM

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090 BSC		2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

- STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE

  - 4. DRAIN

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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